April 2005

FDS6673AZ 30 Volt P-Channel PowerTrench[®] MOSFET



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Features

- -14.5 A, -30 V. $R_{DS(ON)} = 7.2 \text{ m}\Omega @ V_{GS} = -10 \text{ V}$ $R_{DS(ON)} = 11 \text{ m}\Omega @ V_{GS} = -4.5 \text{ V}$
- Extended V_{GSS} range (-25V) for battery applications
- ESD protection diode (note 3)
- High performance trench technology for extremely low R_{DS(ON)}
- High power and current handling capability

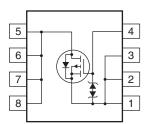
General Description

This P-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers, and battery chargers.

These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $\mathsf{R}_{\mathsf{DS}(\mathsf{ON})}$ specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.





Absolute Maximum Ratings $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter			Ratings	Units
V _{DSS}	Drain-Source Voltage		-30	V	
V _{GSS}	Gate-Source Ve	oltage		<u>+</u> 25	V
I _D	Drain Current	- Continuous	(Note 1a)	-14.5	А
		- Pulsed		-50	
P _D	Power Dissipation for Single Operation (Note 1a)			2.5	W
			(Note 1b)	1.2	
			(Note 1c)	1.0	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +175	°C	
Thermal Cha	aracteristics				
R_{\thetaJA}	Thermal Resistance, Junction-to-Ambient		(Note 1a)	50	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		(Note 1)	25	°C/W

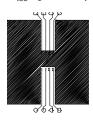
Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS6673AZ	FDS6673AZ	Z 13" 12mm		2500 units

Electrical Characteristics $T_A = 25^{\circ}C$ unless otherwise noted						
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Charact	eristics			1		1
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = -250 \mu\text{A}$	-30			V
$\frac{\Delta \text{BV}_{\text{DSS}}}{\Delta \text{T}_{\text{J}}}$	Breakdown Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}$, Referenced to 25°C		-25		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μA
I _{GSS}	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ
On Charact	eristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250 \ \mu A$	-1	-1.6	-3	V
$\frac{\Delta V_{\text{GS(th)}}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}$, Referenced to 25°C		5.8		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$ \begin{array}{l} V_{GS} = -10 \text{ V}, \text{ I}_{D} = -14.5 \text{ A} \\ V_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -12 \text{ A} \\ V_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -14.5 \text{ A}, \text{ T}_{J} = 125^{\circ}\text{C} \end{array} $		6.0 8.8 7.8	7.2 11 10.4	mΩ
9 _{FS}	Forward Transconductance	V _{DS} = -5 V, I _D = -14.5 A		50		S
Dynamic Ch	aracteristics					
C _{iss}	Input Capacitance	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V},$		4480		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		1190		pF
C _{rss}	Reverse Transfer Capacitance			615		pF
R _G	Gate Resistance	V _{GS} = 15 mV, f = 1.0 MHz		3.8		
Switching C	haracteristics (Note 2)					
t _{d(on)}	Turn–On Delay Time	$V_{DD} = -15 \text{ V}, \text{ I}_{D} = -1 \text{ A},$		22	35	ns
t _r	Turn–On Rise Time	$V_{GS} = -10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$		8	16	ns
t _{d(off)}	Turn–Off Delay Time			134	214	ns
t _f	Turn–Off Fall Time			79	126	ns
Qg	Total Gate Charge	$V_{DS} = -15 \text{ V}, \text{ I}_{D} = -14.5 \text{ A},$		84	118	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = -10 V$		12		nC
Q _{gd}	Gate-Drain Charge	-		19		nC
Drain-Sour	ce Diode Characteristics and Maximun	n Ratings				
I _S	Maximum Continuous Drain-Source Did	ode Forward Current			-2.1	А
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 V, I_S = -2.1 A$ (Note 2)		-0.7	-1.2	V
t _{RR}	Reverse Recovery Time	I _F = -14.5 A,		44		ns
Q _{RR}	Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s} \qquad (\text{Note 2})$		29		nC

Notes:

1. R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.



a) 50°C/W (10 sec) 62.5° C/W steady state when mounted on a 1 in² pad of 2 oz copper



b) 105°C/W when mounted on a .04 in² pad of 2 oz copper

c) 125°/W when mounted

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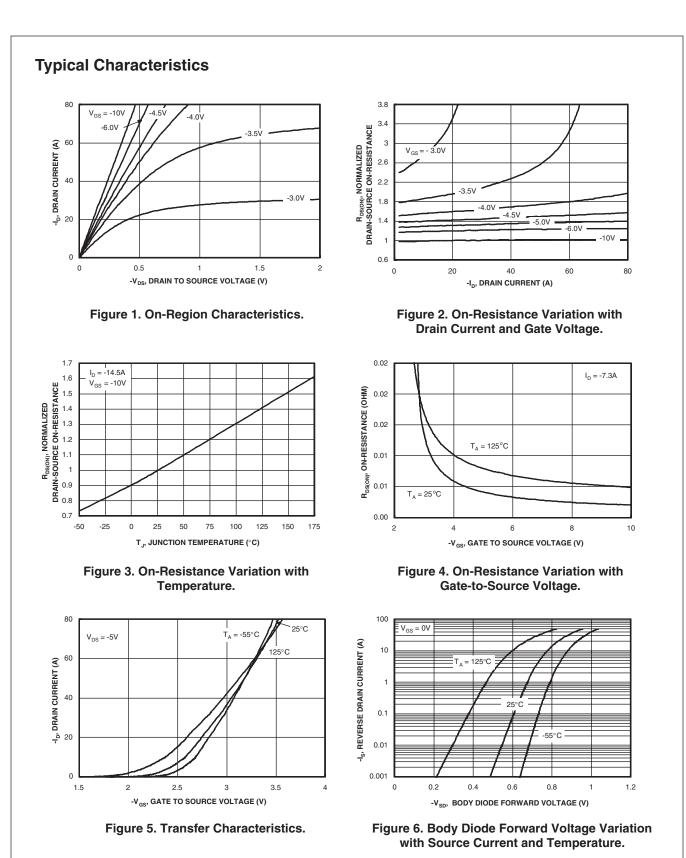
on a minimum pad.

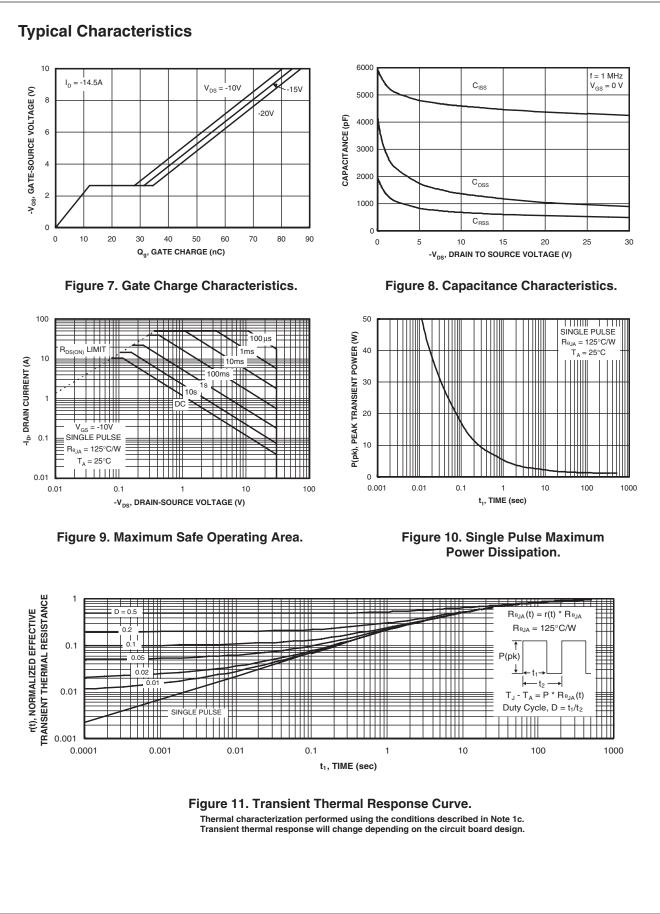
Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

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